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PATENT NUMBER and  
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U.S. UTILITY Patent Application

APPL NUM 10046559	FILING DATE 10/27/2001	CLASS 324	SUBCLASS 158.1	GAU 2862	EXAMINER Jann J. Nguyen
**APPLICANTS: Strom John; 2823					
<p>**CONTINUING DATA VERIFIED: THIS APPLN CLAIMS BENEFIT OF 60/244,432 10/30/2000</p>					
<p>** FOREIGN APPLICATIONS VERIFIED:</p>					
PG-PUB	DO NOT PUBLISH <input type="checkbox"/>	RESCIND <input type="checkbox"/>			
Foreign priority claimed 35 USC 119 conditions met		<input type="checkbox"/> yes <input type="checkbox"/> no <input type="checkbox"/> yes <input type="checkbox"/> no	ATTORNEY DOCKET NO 11532-014001		
Verified and Acknowledged Examiner's initials					
TITLE : Method and process of applying the analysis of scrub mark morphology and location to the evaluation and correction of semiconductor testing analysis, and manufacture					
U.S. DEPT. OF COMM./PAT. & TM-PTO-436 (Rev. 12-94)					

NOTICE OF ALLOWANCE MAILED		Assistant Examiner	CLAIMS ALLOWED	
			Total Claims	Print Claim for O.G.
ISSUE FEE		Primary Examiner	DRAWING	
Amount Due	Date Paid		Sheets Draw.	Figs. Draw.
TERMINAL DISCLAIMER		Application Examiner		
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